INTERNATIONAL STANDARD

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Semiconductor devices –

Part 14-1: Semiconductor sensors – General and classification

Dispositifs à semiconducteurs –

Partie 14-1: Capteurs à semiconducteurs – Généralités et classification

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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FOREWORD

1) The IEC (International Electrotechnical Commission) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of the IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, the IEC publishes International Standards. Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. The IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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6) Attention is drawn to the possibility that some of the elements of this International Standard may be the subject of patent rights. The IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 60747-14-1 has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47E/157/FDIS	47E/170/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 3.

The committee has decided that the contents of this publication remain unchanged until 2005. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual version of this standard may be issued at a later date.

INTRODUCTION

This part of IEC 60747 should be read in conjunction with IEC 60747-1. It provides basic information on semiconductor

– terminology;
– letter symbols;
– essential ratings and characteristics;
– measuring methods;
– acceptance and reliability.

SEMICONDUCTOR DEVICES –

Part 14-1: Semiconductor sensors – General and classification

1 Scope

This part of IEC 60747-14 describes general items concerning the specifications for sensors, which are the basis for specfications given in other parts of this series for various types of sensors. Sensors described in this standard are basically made of semiconductor materials; however, the statements made in this standard are also applicable to sensors using materials other than semiconductor, for example dielectric and ferroelectric materials.

2 Normative references

The following normative documents contain provisions which, through reference in this text, constitute provisions of this part of IEC 60747. For dated references, subsequent amendments to, or revisions of, any of these publictions do not apply. However, parties to agreements based on this part of IEC 60747 are encouraged to investigate the possibility of applying the most recent editions of the normative documents indicated below. For undated references, the latest edition of the normative document referred to applies. Members of ISO and IEC maintain registers of currently valid International Standards.

IEC 60721-2-1:1982, *Classification of environmental conditions – Part 2: Environmental conditions appearing in nature – Temperature and humidity*

IEC 60721-3-0:1984, *Classification of environmental conditions – Part 3: Classification of groups of environmental parameters and their severities – Introduction*
Amendment 1 (1987)

IEC 60747-1:1983, *Semiconductor devices – Discrete devices – Part 1: General*